

DATE:10/25/91

RADIATION TEST SUMMARY

DEVICE TYPE: 6N134 DUAL OPTOCOUPLER
 MANUFACTURER: HEWLETT-PACKARD (HPA)
 PACKAGE TYPE: 16PIN DIP
 TEST DATE: 10/31/91

LOG NUMBER: 1495
 RTR NUMBER: 463B
 LOT NUMBER: N/A

DATE CODE: 9051
 SAMPLE SIZE: 4 + 1 CONTROL

RAD SOURCE: CO60
 FACILITY: JPL

DOSE LEVELS AND RATE, RADS(SI):

20, 35, 50, 75, 100, 150, 200 KRAD(SI) @100 KRAD(SI)/SEC

POST RADIATION EFFECTS (PIE) IN HOURS:

BECAUSE TEST DEVICES WERE BIPOLAR, NO PIE TEST WAS DONE.

MEASURED PARAMETERS	SPECIFICATION FAIL LIMIT	MAX/MIN MEASD. PARA. VALUES	FAILURE LEVEL	REMARKS
IOH1	250 UA MAX	19.908 UA	*	
IOH2	250 UA MAX	20.960 UA	*	
BVR1	5.0 V MIN	9.7840 V	*	
BVR2	5.0 V MIN	9.8148 V	*	
VOL1	0.6 V MAX	0.3764 V	*	
VOL2	0.6 V MAX	0.3796 V	*	
VF1	1.75 V MAX	1.5228 V	*	
VF2	1.75 V MAX	1.5220 V	*	
ICCL	36 MA MAX	27.600 MA	*	
ICCH	28 MA MAX	18.326 MA	*	
CIO1	4.0 PF MAX	1.1754 PF	*	
CIO2	4.0 PF MAX	1.0104 PF	*	
CTR1	100 % MIN	341 %	*	
CTR2	100 % MIN	345 %	*	
TPLH1	100 NS MAX	36.730 NS	*	
TPLH2	100 NS MAX	37.710 NS	*	
TPHL1	90 NS MAX	49.960 NS	*	
TPHL2	90 NS MAX	48.030 NS	*	

* = NO FAILURE AT ANY MEASURED DOSE LEVEL TO 200 KRAD(SI).

NOTES:

- 1) IRRADIATION TEST CONDUCTED IN ACCORDANCE WITH APPLICABLE JPL RADIATION TEST REQUIREMENTS DOCUMENT AND MIL-STD-883, METHOD 1019, EXCEPT FOR DOSE RATE.
- 2) PARAMETRIC FAILURE RESULTS WHEN ANY PIN OF ANY TEST DEVICE EXCEEDS THE PRE-RADIATION SPECIFICATION FAIL LIMITS SHOWN ABOVE.